

<b>Notice of References Cited</b>	Application/Control No. 10/569,968	Applicant(s)/Patent Under Reexamination DEMIR ET AL.	
	Examiner RICARDO E. LOPEZ	Art Unit 1786	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Drew et al., Nano Letters, Vol. 3, No. 2, pgs. 143-147, January 17, 2003
	V	
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